Search N	lotes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/820,980	KHARE ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

SEARCHED			
Class	Subclass	Date	Examiner
709	225	6/8/2007	S.C.
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	6/8/2007	S.C.
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